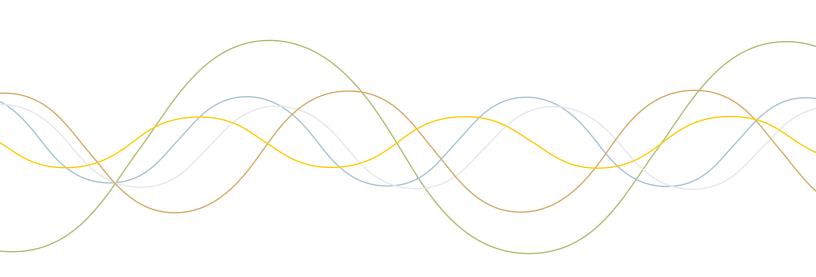


Portable One

Audio Precision Quality in a Portable Test Set

Unmatched Portable Performance





Portable One: Unparalled Precision in a Portable Package



The Portable One family of audio test instruments—at home on the bench or rugged in the field.

With thousands of units sold, you'll find the Portable One family of audio analyzers in operation around the world in maintenance, engineering and production facilities. Whether in broadcast, communications, bench or production use, Portable One offers a complete easy-to-use audio test set housed in a rugged case ready for almost anything. With twelve different measurement functions selectable at the push of a button, Portable One is comprehensive while remaining user-friendly. Its popularity is no less due to its outstanding performance specifications; yet Portable One is as affordable as lower-performing test sets.

Analog Only or full Dual Domain—Analog and Digital

The Portable One Plus Access

Portable One Plus *Access* includes comprehensive analog generation and measurement, with two outputs and two inputs. Easy-to-set-up sweep capability produces graphs of frequency response, distortion vs. frequency and even amplitude sweeps. Non-volatile storage of up to 30 tests allows easy one-button recall of your favorite test setup. Connect Portable One to a compatible printer and produce reports incorporating high-resolution graphs. If you work with digital audio, the **Portable One Dual Domain**® model adds AES3/SPDIF audio and interface measurement capabilities to the comprehensive analog capabilities of the Portable One family.

Analog+Digital+AES3/SPDIF: the Portable One Dual Domain

Portable One Dual Domain® is a comprehensive audio test set for both analog and digital audio, as well as for generation and measurement of AES3/SPDIF digital interface characteristics such as jitter. Like our 2700 Series family of instruments, Portable One Dual Domain features true dual domain architecture. Digital signals are generated and measured purely in the digital domain, resulting in the extremely low distortion and noise residuals necessary for making useful digital audio measurements.

Unparalleled Precision

Low Distortion

Analog System THD+N 80 kHz BW **-92 dB**Digital Distortion THD+N ≤**-140 dB**High Analog Bandwidth

Signal Generation to 120 kHz

Low Noise

22 Hz-22 kHz < **-114 dBu** A-weighted < **-118 dBu**

Wide Input Voltage Range

Input Range 80 mV-250 V in 10 dB steps

Flat Response

20 Hz-20 kHz ±0.05 dB

Low Crosstalk

Input < -120 dB

Output < -110 dB

Low Jitter

Generator < 0.8 ns

Analyzer < 1.6 ns



Performance, Measurement Power, and Ease-of-Use

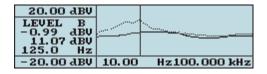
Easy to Use

Measurement functions are simply selected from the front panel. Just press a button

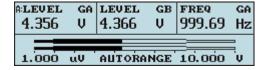


and make the measurement. Selection of analog and digital inputs is clearly indicated on the front panel with LED legends. Portable One makes graphs of swept measurements in real time

on the high contrast back-lit LCD display, including both frequency and amplitude sweeps. Hard copy high-resolution graphs, compact screen-sized graphs or tabular data



listings can be made from your Portable One to laser or ink jet printers at the touch of a button. Bargraphs can display measurements ranging from AC mains power line



distortion to digital interface error rate ...and nearly everything in between. Separate buttons and knobs provide independent control of frequency and amplitude. The buttons provide large and medium steps (decade and 1/3 octave steps for frequency, 10 dB and 1 dB for amplitude), with knobs



for finer resolution. When not otherwise used, the setting knobs and buttons also provide a convenient human interface for scrolling display cursors and for entry of other settings and data.

Stereo:

Portable One Dual Domain is a true two channel instrument. Both analog and digital level functions measure both inputs simultaneously. Phase and level ratio measure-



ments are also available.

Full Range of Analog & Digital Testing Facilities:

Portable One Dual Domain provides complete and parallel measurement capabilities for both analog and digital audio signals. Measurements common to both domains include: Amplitude, Noise, Level (2 channels simultaneously), Frequency, Phase, THD+N, SMPTE/DIN, IMD, Crosstalk and Level Ratio. Standard A-weighting, CCIR 468, and LP/HP filters are included in both domains. RMS and quasi-peak (CCIR 468) detectors are available in both domains.

Analog Performance:

The low distortion transformer-coupled analog generator supplies a full 30.17 dBu (+29.6 dBm into 600 Ω) at selectable (40 Ω , 150 Ω or 600 Ω) source impedances. Extremely low analyzer noise and residual distortion support measurement of high performance digital devices.

Analog Convenience Functions:

In addition to the above measurements, the analog GEN LOAD function measures the input resistance of your device at any frequency you choose and makes swept impedance measurements (including loudspeakers).

AC MAINS CHECK measures the voltage, frequency and distortion of the power line without hazardous direct connections. BARGRAPH display in AC MAINS CHECK function provides a visible history of maximum and minimum mains voltage excursions.

aac mains 117.0 V		z.	FREQ 59.987	Hz
A:GEN:SINE	1.000	V	1.000	kHz
SELF TEST				

The dBq unit (dB referred to the present analog generator amplitude) is useful for compression threshold measurements or rapid response sweeps at several different absolute levels, as well as for input to output gain/loss measurements.

600 Ω Analog Input Terminations are individually switchable for each channel of the analog analyzer.

Turn on Portable One: Audio Testing to Meet Your Challenges

Comprehensive Analog and Digital Functions

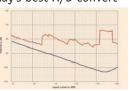
Digital Performance:

Portable One Dual Domain uses a true DSP-implemented analyzer for digital measurements, which results in –130 dB residual THD+N, 0.01 dB flatness, and –140 dBFS residual noise. Other mixed-signal test sets in



the same price range have no digital analyzer, but use a D/A converter and an analog analyzer. These architectures "bottom out" at -70 dB to -84 dB residual THD+N (12–14 bit effective performance), and 0.1 dB flatness. With today's best A/D convert-

ers measuring
-108 dB to -112 dB
THD+N, their real
performance is invisible to these
mixed signal analyzers ...buried under
the analyzer's noise



wisible to these

A competitive instrument lacking a DSP analyzer produces false THD+N mixed signal analyz-readings (red trace) from a popular A/D converter; but both the ers ...buried under

Portable One Dual Domain and the Audio Precision 2700 Series graph the true performance of the converter (from 5 dB to 28 dB lower), and distortion floor.

A competitive instrument lacking a DSP analyzer produces false THD+N the bound a popular produces from a popular produces from the popular produces from the produces fr

Separate & Independent Analog & Digital Generators:

Often necessary for dual domain testing. You may, for example, drive the inputs of an A/D converter with the low-distortion analog sine while simultaneously driving the converter's digital reference (house sync) input with the digital generator. Then, add jitter or vary the sample rate to see the ef-

fect on THD+N, IMD, or noise. Competitive units can drive only one domain at a time or use their analog generator to create the digital jitter, and thus can't make this measurement at all.

Separate Digital Inputs & Outputs:



Three I/O formats: XLR, BNC, and optical (Toslink®). All are completely separate from the analog audio XLR connectors, permitting both digital and analog generators to operate simultaneously. No cable changes required to go from A/D to D/A to D/D to A/A testing of a digital tape machine, for example.

Digital & Analog Monitors:

Listen to all measurements in the digital

and analog domains over the internal loudspeaker or a pair of head-



phones. In the analog domain, monitor signals or distortion. In the digital domain, the incoming signal, distortion, or jitter can all be monitored.

Jitter Meter:

Portable One Dual Domain includes jitter measurement in nanoseconds or in Unit Intervals. Two filter selections are provided

0.484 UI	4.99 Vpp	400.46 Hz
D:GEN:SINE	1.0000 Ffs	997.00 Hz
UN-WTD	HP: 50 Hz	RMS

for the jitter meter: a 700 Hz high-pass filter used for residual jitter measurements according to AES standards, and a 50 Hz highpass filter for jitter response measurements.

Other Interface Signal Measurements:

Portable One Dual Domain measures key digital I/O interface parameters in addition to jitter, including sample rate, AES signal voltage, frame delay through the device under test, and delay of the input signal relative to a house sync reference (frame or block).

	xlr loz g 2.98 Vpp	
D:GEN:SINE	1.0000 Ffs	$1.0000\mathrm{kHz}$
REF: STAT	INP:24bit	OUT BLOCK

Flexible Interface Impairment Simulation:

Flexible digital interface testing is vital for troubleshooting and verifying performance of digital audio at the systems level. Portable One Dual Domain allows simulation of real world transmission and interface problems.

JITTER	GENERA?	ror		
D:JIT:SINE	0.201	ШI	1.002	kHz

Vary the digital output signal to test the acceptance range of your digital devices. Set sample rate anywhere from 28.8 kHz to 99.9999 kHz, not just at the three standard frequencies. Inject jitter amplitude from 0 UI to 2.5 UI (415 ns at 48 kHz) in 0.01 UI (1.6 ns) steps, or 0 UI to 25.5 UI (4150 ns) in 0.1 UI (16 ns) steps.

challenges

Injected jitter frequency can be set from 10 Hz to 38.8 kHz, not just to a fixed frequency. Adjust output signal amplitude continuously from zero to 5.12 Volts in 5 mV increments, not just at a few steps. Only the Portable One Dual Domain provides this flexibility in a portable analyzer.

Independent Interface I/O Word Lengths:

Word length (resolution) of digital input and output are independently set from 16 to 24 bits. Output resolution is set to match the device under test to assure proper

D:RATE 48000.0 Hz		260.72 UI
D:GEN:SINE	-60.00 dBfs	$1.0001~\mathrm{kHz}$
REF: MEAS	INP:24bit	OUT BLOCK

dither. Input resolution must be set to exclude signal in the AUX bits or other low-level bit activity meaningless to the desired measurement.

Independent Input & Output Sample Rates:

Lets you test sample rate converters. Measurement of the incoming embedded audio signal can be referred to the incoming sample rate, status byte indication of rate, or the outgoing generator rate.

D:SEND:CONS	EMPH: NONE	SR: 32 kHz
D:INP:CONS	EMPH: NONE	SR: 32kHz
COPY: NO		NO ERRORS
COPY: NO		VALID

Data ✓ Error Testing Capability for Digital Audio Signals:

Stimulate the test device with random data and display current or totaled error measurements on both channels. The signal and analysis techniques are compatible with the BITTEST feature of our System products, so you can test a transmission link end-to-end

			_			B71A	св D2hex
Ξ	₹	іот		•		10000	

with a Portable One Dual Domain at one end and a System Two, Cascade or 2700 Series dual domain instrument at the other.

Other Digital Convenience Functions:

DERROR GA ERROR GB DATA

Digital Status bytes are displayed and set in high-level English.

	0		0	6FEA40hex
24	16	8		ACTIVEBIT
D:ERROR	GA	ERROR	GB	DATA GA
	0		0	5A0D60hex

Error flag displays for confidence, lock, coding, parity errors and the validity bit are included.

Additional active bit and actual bit displays on the panel help determine the word length of the incoming signal and detect stuck bits.

Digital Dither:

Portable One Dual Domain includes a full complement of dither selections—triangular and rectangular probability distribution functions; white or shaped spectrum.

Dither amplitude is automatically set to the proper value for the output word length and the selected probability function.

Sample & Frame Sync:

Synchronize Portable One Dual Domain sample and frame sync to the digital reference (house sync) input.

Digital Pass Mode:

Sends the input digital audio content to the output while modifying status bytes, validity bit, etc. Portable One Dual Domain can thus be used as a problem-solver between incompatible equipment.

Signal Monitoring Outputs:

GA

A digital signal appropriate for syncing an external oscilloscope may be derived from the input sample rate, output sample rate, input block rate, output block rate, digital audio waveform, jitter signal, or the detected interface errors. A buffered version of the balanced AES3 signal from the XLR input is also available, which coupled with the high input impedance of the XLR in bridging mode allows non-intrusive digital line measurements with conventional ground-referenced oscilloscopes.

Save your test setups—with measured data and print reports

Save & Recall Tests:

Save 30 instrument setups, including sweep results data, time-stamped from the internal clock calendar. Use for repeatable, easy

bench and production testing or when in the field, for storing test data to be printed or analyzed later. Each saved test includes all settings

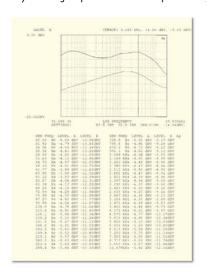


SF	1VE	CANCEL	SCR	OLL UP
15	#####	LZPAMPL	371817	00:22
	XTALK empty			
18	GRAPH	/A:FREQ A:FREQ	951112	13:58
	ECALL	PAGE	SCR	

for the entire instrument, a default description or your own title for the test, the date and time, and the last test sweep result data.

Print Graphs And Test Results:

Portable One prints graphs, panel setups and measured data either to laser (PCL compatible) or inkjet printers. Front panel keys





select two sizes of graph output (including cursor data), tabular sweep data, bargraphs and front panels for printing.

For a quick print, a compact graph provides a direct replication of the LCD screen. A larger graph printout covering approximately half a page (360x280 pixels with grid lines) allows finer detail to be shown. Both graphs show key instrument setup parameters as well. Tabular data values for all swept points may be printed in order to preserve exact reading values.

The bargraph displays, with their useful minimum/maximum indicators print just as they are seen on the display, as do any desired instrument panels. Various printouts may be combined on one page, to include graphs, bargraphs and numeric data.

INTERNAL CLOCK/CALENDAR:

An internal clock/calendar automatically stamps the time and date on setups and data as they are saved.

PRINTER PCL GRAPH	FREQ STEP 1.0000 kHz
	 AMPL STEP

You can view or set the clock/calendar from the Setup panel.

GPIB Control:

An IEEE-488 Interface is built in to allow control of the instrument in an automatic test environment. National Instruments LabWindows/CVI and LabVIEW drivers are available. A LabWindows/CVI soft front panel program is provided with a Windows user interface for real-time instrument control through the GPIB interface. The LabVIEW driver is provided with a Getting Started VI and sample VIs.



Frequency Range	10 11= += 120 1.11-	
Frequency Accuracy	10 Hz to 120 kHz ±0.5 %	
Amplitude Range Balanced	(20 Hz to 30 kHz) <0.25 mV to 26.25 Vrms [-70 dBu to	
Unbalanced	+30.6 dBu] <0.25 mV to 13.12 Vrms [-70 dBu to +24.6 dBu]	SMPTE (DIN) I Test Signal Con
Amplitude Accuracy	±0.2 dB [±2.3 %] at 1 kHz	IMD Measured
Amplitude Resolution Flatness (1 kHz ref)	0.01 dB	
10 Hz-20 kHz Residual THD+N	±0.05 dB	Measurement R Accuracy
25 Hz-20 kHz	\leq (0.0025% + 3 μ V), 80 kHz BW [-92 dB]	Residual IMD
Square Wave Frequency Range	20 Hz-30 kHz	W 0 Florth-
Amplitude Range		Wow & Flutter Test Signal Con
Balanced Unbalanced	0.71 mVpp to 34.73 Vpp 0.71 mVpp to 17.36 Vpp	Accuracy (4 Hz Detection Mode
Amplitude Accuracy Rise/fall time	±0.3 dB [±3.5 %] at 400 Hz Typically 2.5–3.0 μs	Residual W+F
SMPTE (or DIN) Test Signals v	vith option "P1-IMD"	
LF Tone HF Tone Range	50, 60, 70, or 250; all ±1.0 % 7 kHz or 8 kHz (±1 %)	DIGITAL SIGN
Mix Ratio	4:1 (LF:HF)	Output Formats
Residual IMD	0.0015 % [-96.5 dB], 60 Hz + 7 kHz or 250 Hz + 8 kHz	Sample Rates
OUTPUT CHARACTERISTICS	Calastable belowed an unbalanced	Sample Rate Ac
Source Configuration Source Impedances	Selectable balanced or unbalanced	Word Length
Balanced Unbalanced	40 Ω (± 2 Ω), 150 Ω (± 2 Ω), or 600 Ω (± 6 Ω) 40 Ω (± 2 Ω)	Sine Wave Frequency Rang
Output Current Limit Max Output Power	75 mA peak	Frequency Reso
Balanced Unbalanced	+30.0 dBm into 600 Ω (Rs = 40 Ω) +23.9 dBm into 600 Ω (Rs = 40 Ω)	Flatness
Output Related Crosstalk	≤-110 dB or 10 µV, whichever is	Residual Distor
(10 Hz-20 kHz)	greater	Square Wave Frequency Rang
ANALOG ANALYZER	rice	Frequencies ava
ANALOG INPUT CHARACTERIST Input Ranges	80 mV to 250 V in 10 dB steps	SMPTE/DIN IM
Maximum Rated Input Input Impedance	350 Vpk, 140 Vrms (dc to 20 kHz); overload protected	Upper Tone Rar Lower Tone Rar
Balanced (each side) Unbalanced	Nominally 100 k Ω // 150–200 pF Nominally 100 k Ω // 150–200 pF	Amplitude Rati Residual Distor
Terminations	Selectable 600 Ω ±1 %	Random Gener
CMRR 80 mV–2.5 V range Input Related Crosstalk	≥70 dB, 50 Hz-20 kHz ≤-120 dB or 1 µV, whichever is	Waveform
10 Hz-20 kHz	greater	Dither (all wav
Wideband Amplitude/Noise F Measurement Range	<1 μVrms to 140 Vrms [-118 dBu to	Probability Dist
Accuracy (1 kHz)	+45 dBu] ±0.2 dB [±2.37 %] unweighted	Spectral Distrib
Flatness (1 kHz ref)	±0.05 dB (20 Hz-20 kHz)	Amplitude
Bandwidth Limiting Filters LF –3 dB HF –3 dB	<10 Hz; 400 Hz ±5 % (3-pole) 22 kHz; 30 kHz; 80 kHz (3-pole), or 300 kHz	AES/EBU INT Interface Sign
Weighting Filters	ANSI-IEC "A"; CCIR-QPK; CCIR-ARM;	Amplitude Rang
Optional Filters	CCIR-RMS Up to 2 (Aux 1 and Aux 2)	Balanced (XL Unbalanced
Detection	RMS (i=60 ms); AVG; QPK (CCIR Rec 468)	Channel Status
Residual Noise 22 Hz–22 kHz BW	·	Validity Flag
A-weighted CCIR-QPK	≤1.5 µV [-114 dBu] ≤1.0 µV [-118 dBu] ≤5.0 µV [-104 dBu]	AES/EBU Impa Induced Jitter
Frequency Meter Related (bot		Jitter Freq Rang
Measurement Range	10 Hz-200 kHz	Jitter Amplitud
	±0.01 % [±100 PPM] 5 digits	
Resolution Phase Measurement Related		RMS respons
Resolution Phase Measurement Related Measurement Ranges	±180, +90/-270, or -90/+270 deg +2.0 deg	RMS respons Peak respons
Resolution Phase Measurement Related Measurement Ranges Accuracy 20 Hz–20 kHz Resolution	±2.0 deg 0.1 deg	RMS respons Peak respons Spurious Jitter Jitter & Ref
Resolution Phase Measurement Related Measurement Ranges Accuracy 20 Hz–20 kHz Resolution Level Meter Related (both ch	±2.0 deg 0.1 deg annels)	RMS respons Peak respons Spurious Jitter Jitter & Ref Jitter On
Resolution Phase Measurement Related Measurement Ranges Accuracy 20 Hz–20 kHz Resolution Level Meter Related (both ch	±2.0 deg 0.1 deg annels)	RMS respons Peak respons Spurious Jitter Jitter & Ref Jitter On REFERENCE IN Input Formats
Resolution Phase Measurement Related Measurement Ranges Accuracy 20 Hz–20 kHz Resolution Level Meter Related (both ch. Measurement Range	±2.0 deg 0.1 deq annels) 10 mV to 140 V for specified accuracy and flatness, useable to -100 µV [-38 dBu to + 45 dBu] ±0.1 dB + 100 µV	RMS respons Peak respons Spurious Jitter Jitter & Ref Jitter On REFERENCE IN Input Formats
Resolution Phase Measurement Related Measurement Ranges Accuracy 20 Hz–20 kHz Resolution Level Meter Related (both ch. Measurement Range	±2.0 deg 0.1 deg annels) 10 mV to 140 V for specified accuracy and flatness, useable to <100 µV [-38 dBu to + 45 dBu]	RMS respons Peak respons Spurious Jitter Jitter & Ref Jitter On REFERENCE IN Input Formats Input Sample R Lock Range
Resolution Phase Measurement Related Measurement Ranges Accuracy 20 Hz-20 kHz Resolution Level Meter Related (both ch. Measurement Range Accuracy (1 kHz) Flatness (1 kHz ref) Bandpass Amplitude Function	±2.0 deg 0.1 deg annels) 10 mV to 140 V for specified accuracy and flatness, useable to <100 μV [-38 dBu to + 45 dBu] ±0.1 dB + 100 μV (Vin >10 mV) ±0.05 dB (20 Hz-20 kHz)	RMS respons Peak respons Spurious Jitter Jitter & Ref Jitter On REFERENCE INI Input Formats Input Sample F Lock Range DIGITAL ANA
Resolution Phase Measurement Related Measurement Ranges Accuracy 20 Hz-20 kHz Resolution Level Meter Related (both ch. Measurement Range Accuracy (1 kHz) Flatness (1 kHz ref) Bandpass Amplitude Function Tuning Range (f _o)	±2.0 deg 0.1 deq annels) 10 mV to 140 V for specified accuracy and flatness, useable to -100 µV [-38 dBu to + 45 dBu] ±0.1 dB + 100 µV (Vin >10 mV) ±0.05 dB (20 Hz-20 kHz)	RMS respons Peak respons Spurious Jitter Jitter & Ref Jitter On REFERENCE INI Input Formats Input Sample F Lock Range DIGITAL ANA
Resolution Phase Measurement Related Measurement Ranges Accuracy 20 Hz-20 kHz Resolution Level Meter Related (both ch. Measurement Range Accuracy (1 kHz) Flatness (1 kHz ref) Bandpass Amplitude Function Tuning Range (f _o) Bandpass Response Accuracy (at f _o)	±2.0 deg 0.1 deg annels) 10 mV to 140 V for specified accuracy and flatness, useable to <100 μV [-38 dBu to + 45 dBu] ±0.1 dB + 100 μV (Vin >10 mV) ±0.05 dB (20 Hz-20 kHz)	RMS respons Peak respons Spurious Jitter 8. Ref Jitter 8. Ref Jitter On Input Formats Input Sample R Lock Range DIGITAL ANA DIGITAL INPUT Input Formats Sample Rates
Resolution Phase Measurement Related Measurement Ranges Accuracy 20 Hz-20 kHz Resolution Level Meter Related (both ch. Measurement Range Accuracy (1 kHz) Flatness (1 kHz ref) Bandpass Amplitude Function Tuning Range (fo) Bandpass Response Accuracy (at fo) THD+N / SINAD Function	±2.0 deg 0.1 deq annels) 10 mV to 140 V for specified accuracy and flatness, useable to <100 μV [-38 dBu to + 45 dBu] ±0.1 dB + 100 μV (Vin >10 mV) ±0.05 dB (20 Hz-20 kHz) 20 Hz to 120 kHz 0=5 (2-pole) ±0.3 dB, 20 Hz-120 kHz	RMS respons Peak respons Spurious Jitter 8. Ref Jitter 8. Ref Jitter On Input Formats Input Sample R Lock Range DIGITAL ANA DIGITAL INPUT Input Formats Sample Rates Word Length
Resolution Phase Measurement Related Measurement Ranges Accuracy 20 Hz-20 kHz Resolution Level Meter Related (both ch. Measurement Range Accuracy (1 kHz) Flatness (1 kHz ref) Bandpass Amplitude Function Tuning Range (f,) Bandpass Response Accuracy (at f,) THD+N / SINAD Function Fundamental Range Measurement Range	±2.0 deg 0.1 deq annels) 10 mV to 140 V for specified accuracy and flatness, useable to <100 μV [-38 dBu to + 45 dBu] ±0.1 dB + 100 μV (Vin >10 mV) ±0.05 dB (20 Hz -20 kHz) 20 Hz to 120 kHz Q=5 (2-pole) ±0.3 dB, 20 Hz-120 kHz 10 Hz to 100 kHz, THD+N mode .001 %-100 %	RMS respons Peak respons Spurious Jitter Jitter & Ref Jitter On REFERENCE IN Input Formats Input Sample R Lock Range DIGITAL ANA DIGITAL INPU Input Formats Sample Rates Word Length EMBEDDED AU
Resolution Phase Measurement Related Measurement Ranges Accuracy 20 Hz-20 kHz Resolution Level Meter Related (both ch. Measurement Range Accuracy (1 kHz) Flatness (1 kHz ref) Bandpass Amplitude Function Tuning Range (f _o) Bandpass Response Accuracy (at f _o) THD+N / SINAD Function Fundamental Range Measurement Range Measurement Range	±2.0 deg 0.1 deq annels) 10 mV to 140 V for specified accuracy and flatness, useable to <100 μV [-38 dBu to + 45 dBu] ±0.1 dB + 100 μV (Vin >10 mV) ±0.05 dB (20 Hz-20 kHz) 10 10 Hz to 120 kHz —5 (2-pole) ±0.3 dB, 20 Hz-120 kHz 10 Hz to 100 kHz, THD+N mode .001 %-100 % 400 Hz-1 kHz	RMS respons Peak respons Spurious Jitter Jitter & Ref Jitter to n REFERENCE INI Input Formats Input Sample R Lock Range DIGITAL ANA DIGITAL INPU Input Formats Sample Rates Word Length EMBEDDED AU Wideband Lev Range
Resolution Phase Measurement Related Measurement Ranges Accuracy 20 Hz-20 kHz Resolution Level Meter Related (both ch. Measurement Range Accuracy (1 kHz) Flatness (1 kHz ref) Bandpass Amplitude Function Tuning Range (f,) Bandpass Response Accuracy (at f,) THD+N / SINAD Function Fundamental Range Measurement Range SINAD Range Accuracy Measurement Bandwidth	±2.0 deg 0.1 deq annels) 10 mV to 140 V for specified accuracy and flatness, useable to <100 μV [-38 dBu to + 45 dBu] ±0.1 dB + 100 μV (Vin >10 mV) ±0.05 dB (20 Hz-20 kHz) 20 Hz to 120 kHz Q=5 (2-pole) ±0.3 dB, 20 Hz-120 kHz 10 Hz to 100 kHz, THD+N mode .001 %-100 % 400 Hz-1 kHz ±1 dB, 20 Hz-120 kHz harmonics	RMS respons Peak respons Spurious Jitter Jitter & Ref Jitter On REFERENCE INI Input Formats Input Sample R Lock Range DIGITAL ANA DIGITAL INPUT Input Formats Sample Rates Word Length EMBEDDED AU Wideband Leve Range Frequency Rang Accuracy
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Resolution Phase Measurement Related Measurement Ranges Accuracy 20 Hz-20 kHz Resolution Level Meter Related (both ch. Measurement Range Accuracy (1 kHz) Flatness (1 kHz ref) Bandpass Amplitude Function Tuning Range (f,) Bandpass Response Accuracy (at f,) ThD+N / SINAD Function Fundamental Range Measurement Range Measurement Range SINAD Range Accuracy Measurement Bandwidth LF-3 dB HF-3 dB	±2.0 deg 0.1 deq annels) 10 mV to 140 V for specified accuracy and flatness, useable to <100 µV [-38 dBu to + 45 dBu] ±0.1 dB + 100 µV (Vin >10 mV) ±0.05 dB (20 Hz-20 kHz) 20 Hz to 120 kHz 0=5 (2-pole) ±0.3 dB, 20 Hz-120 kHz 10 Hz to 100 kHz, THD+N mode .001 %-100 % 400 Hz-1 kHz ±1 dB, 20 Hz-120 kHz harmonics <10 or 400 Hz 22k, 30k, 80k, or 300 kHz ≤(0.0025% + 3.0 µV), 80 kHz BW	RMS respons Peak respons Spurious Jitter & Ref Jitter & Ref Jitter On REFERENCE INI Input Formats Input Sample R Lock Range DIGITAL ANA DIGITAL INPUT Input Formats Sample Rates Word Length EMBEDDED AU Wideband Leve Range Frequency Rang Accuracy Flatness High pass Filte
Resolution Phase Measurement Related Measurement Ranges Accuracy 20 Hz-20 kHz Resolution Level Meter Related (both ch. Measurement Range Accuracy (1 kHz) Flatness (1 kHz ref) Bandpass Amplitude Function Tuning Range (f,) Bandpass Response Accuracy (at f,) ThD+N / SINAD Function Fundamental Range Measurement Range SINAD Range Measurement Range Measurement Bandwidth LF-3 dB HF-3 dB Residual THD+N 25 Hz-20 kHz	±2.0 deg 0.1 deq annels) 10 mV to 140 V for specified accuracy and flatness, useable to <100 μV [-38 dBu to + 45 dBu] ±0.1 dB + 100 μV (Vin >10 mV) ±0.05 dB (20 Hz-20 kHz) 10 Hz to 120 kHz Q=5 (2-pole) ±0.3 dB, 20 Hz-120 kHz 10 Hz to 100 kHz, THD+N mode .001 %-100 % 400 Hz-1 kHz ±1 dB, 20 Hz-120 kHz harmonics <10 or 400 Hz 22k, 30k, 80k, or 300 kHz	RMS respons Peak respons Spurious Jitter & Ref Jitter & Ref Jitter On REFERENCE INI Input Formats Input Sample R Lock Range DIGITAL ANA DIGITAL INPUT Input Formats Sample Rates Word Length EMBEDDED AU Wideband Leve Range Frequency Rang Accuracy Flatness High pass Filter Low pass Filter
HF -3 dB Residual THD+N	±2.0 deg 0.1 deq annels) 10 mV to 140 V for specified accuracy and flatness, useable to <100 µV [-38 dBu to + 45 dBu] ±0.1 dB + 100 µV (Vin >10 mV) ±0.05 dB (20 Hz-20 kHz) 20 Hz to 120 kHz 0=5 (2-pole) ±0.3 dB, 20 Hz-120 kHz 10 Hz to 100 kHz, THD+N mode .001 %-100 % 400 Hz-1 kHz ±1 dB, 20 Hz-120 kHz harmonics <10 or 400 Hz 22k, 30k, 80k, or 300 kHz ≤(0.0025% + 3.0 µV), 80 kHz BW	REFERENCE INI Input Formats Input Sample R Lock Range DIGITAL ANA DIGITAL INPUT Input Formats Sample Rates Word Length EMBEDDED AUI Wideband Leve Range Frequency Rang Accuracy

specifications

SMPTE (DIN) IMD Function	with option "P1-IMD"	
Test Signal Compatibility	40-250 Hz and 3 kHz-20 kHz in	
IMD Measured	0:1 to 8:1 ratio Amplitude modulation products of	
Measurement Range	the HF tone. <0.0025 %-20 %	Narrow Band Amplitude
Accuracy	±1 dB per SMPTE RP-120-1983,	Frequency Range
Residual IMD	DIN 45403 ≤0.0025% [-92 dB], 60 + 7 kHz or	Filter Shape
Man 9 Flutton Function	250 + 8 kHz	THD+N Measurements
Now & Flutter Function Test Signal Compatibility	2.80 kHz-3.35 kHz	Fundamental Range
Accuracy (4 Hz)	±(5 % of reading + 0.002 %)	Residual THD+N
Detection Modes Residual W+F	IEC/DIN; NAB; JIS ≤0.005% Weighted; ≤0.01%	High pass Filters Low pass Filters
	Unweighted	
DIGITAL SIGNAL GENERA	ATOR	Weighting Filters
DIGITAL OUTPUT CHARACTE		SMPTE (DIN) IMD Function wit
Output Formats	AES/EBU (per AES3-1992); SPDIF- EIAJ; Optical	Test Signal Compatibility
Sample Rates	28.8 kHz-99.9999 kHz	IMD Measured
Sample Rate Accuracy	±0.002% [±20 PPM] lockable to external reference	Measurement Range
Word Length	16 to 24 bits (even values)	Accuracy
Sine Wave Frequency Range	10 Hz to 47 % of sample rate	Residual IMD (0 dBFS)
	(22.56 kHz at 48 ks/s)	Frequency Measurements
Frequency Resolution	Sample Rate ÷ 2 ²³ (typically 0.006 Hz at 48 ks/sec)	Frequency Measurements Range
Flatness Residual Distortion	±0.001 dB ±0.00001 % [-140 dB]	Phase Measurement Related
Square Wave	±0.00001 % [-140 dB]	Measurement Ranges
Frequency Range	10 Hz to 1/6 sample rate	Accuracy Resolution
Frequencies available	f _s ÷ 4096 to f _s ÷ 6, in even integer divisors	BITTEST Measurement
SMPTE/DIN IMD Waveform		Measurement
Upper Tone Range	Choice of 7 kHz or 8 kHz	
Lower Tone Range Amplitude Ratio	Choice of 50 Hz, 60 Hz, 70 Hz, or 250 Hz 4:1 (LF:HF)	DIGITAL INTERFACE MEASU
Residual Distortion	≤0.00001 % [-140 dB] at 4:1 ratio	AES/EBU Impairments, Real Ti Input Sample Rate
Random Generator Wavefor		
Waveform	Compatible with Audio Precision BITTEST	Output to Input or Reference Input to Input Delay
Dither (all waveforms)		
Probability Distribution	Triangular or rectangular; independent for each channel	AES/EBU Input Voltage
Spectral Distribution	Flat (white) or Shaped (+6 dB/oct,	Balanced
Amplitude	triangular only) Automatically tracks word length or off	Unbalanced
AES/EBU INTERFACE GE		Jitter Amplitude (500 Hz)
Interface Signal	NERATION	Jitter Flatness
Amplitude Range		
Balanced (XLR) Unbalanced (BNC)	0–5.11 Vpp, into 110 Ω in 5 mV steps 0–1.62 Vpp, into 75 Ω in 1.6 mV steps	Residual Jitter, peak calibrated
Channel Status Bits	English language decoded, Professional/Consumer	Spurious Jitter Products
Validity Flag	Selectable, set or cleared	Channel Status Bits
AES/EBU Impairments		Validity Flag
Induced Jitter Jitter Freq Range	Sine wave 10 Hz to 38.8 kHz	Parity; Signal Confidence;
litter Amplitude	0-1.28 UI (pk), in steps of 0.005 UI	Receiver Lock; Coding Error
	or better 1.3–12.75 UI, in steps of 0.05 UI or	AUXILIARY SIGNALS
Residual Jitter	better	Generator Analog Sync Output; Monitor; Analyzer Reading
RMS response	(total generator/analyzer) peak calibrated ≤0.005 UI (700 Hz-30 kHz BW) ≤0.015 UI (700 Hz-30 kHz BW)	
Peak response Spurious Jitter Products		AUDIO MONITOR
Jitter & Ref Delay Off Jitter On	≤0.0005 UI ≤-30 dB below jitter signal	Power Output
REFERENCE INPUT CHARACT		GENERAL / ENVIRONMENTA
Input Formats	AES/EBU (per AES3-1992)	Power Requirements
Input Sample Rates Lock Range	28.8 kHz-99.9999 kHz ±0.0025% [±25 PPM]	Temperature Range
		Humidity
<u>DIGITAL ANALYZER</u> DIGITAL INPUT CHARACTER:	ISTICS	EMC
Input Formats	AES/EBU (per AES3-1992); SPDIF-	
Sample Rates	EIAJ; Optical	Dimensions
Word Length	28.8 kHz-99.9999 kHz 16 to 24 bits	Weight
EMBEDDED AUDIO MEASURE		Safety
Wideband Level/Amplitude		
Range Frequency Range	0 dBFS to -140 dBFS <10 Hz-22.0 kHz at 48 ks/sec	
Accuracy	±0.01 dB, ≥-90 dBFS	
Flatness High pass Filters	±0.01 dB, 15 Hz-22 kHz 22 Hz, 400 Hz, 2-pole Butterworth	Complete Portable One
Low pass Filters	15 kHz, 20 kHz 6-pole elliptic low-	loadable from the
Weighting Filters	ANSI-IEC "A" weighting; CCIR QPK;	Audio Precision Web s
Residual Noise	CCIR RMS -140 dBFS unweighted; -142 dBFS	

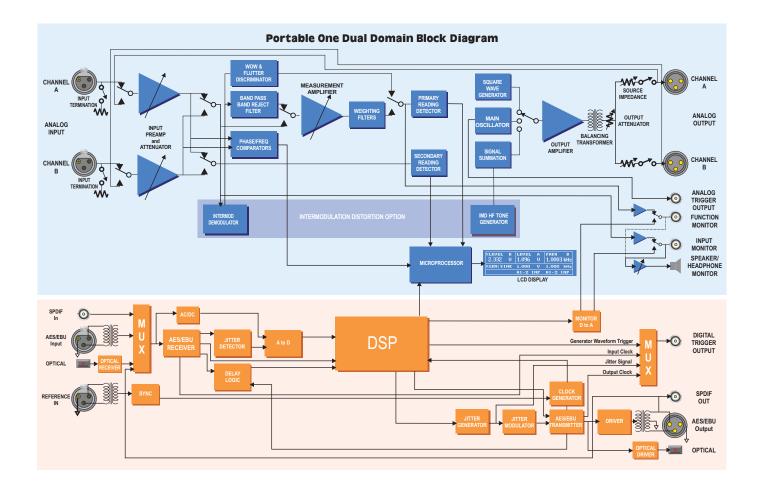
-140 dBFS unweighted; -142 dBFS A-weighted

0.04% to 40% of sample rate
(10 Hz-19.2 kHz at 48.0 ks/sec)
10-pole, Q=19 (BW = 5.3% of f_0)
0.02% to 45% of sample rate (10 Hz-22.0 kHz at 48.0 ks/sec
≤-138 dBFS
22 Hz, 400 Hz 2-pole Butterworth
15 kHz, 20 kHz 6-pole elliptic low-pass
ANSI-IEC "A" weighting; CCIR QPK; CCIR RMS
th option "P1-IMD"
40-250 Hz and 3 kHz-20 kHz in 1:1 to 4:1 ratio
Amplitude modulation products of the HF tone.
<0.0001%-10%
±1 dB per SMPTE RP-120-1983, DIN 45403
≤0.0001% [-120 dB], 60 + 7 kHz c 250 + 8 kHz
5 Hz to 47% of sample rate
±180, +90/-270, or -90/+270 deg
±2.0 deg (20 Hz-20 kHz)
0.1 deg
Compatible with random mode of Audio Precision BITTEST
JREMENTS
ime Displays
±0.002% [±20 PPM] internal ref, ±0.0001% [*1 PPM] external ref
Measures status propagation from
ricasures status propagation nom
the AES/EBU output to the input. Range is 0-192 (frames), resolution
the AES/EBU output to the input. Range is 0–192 (frames), resolution ±60 ns. 400 mV to 10.24 Vpp,
the AES/EBU output to the input. Range is 0–192 (frames), resolution ±60 ns. 400 mV to 10.24 Vpp, ±(10% + 50 mV) 100 mV to 2.56 Vpp,
the AES/EBU output to the input. Range is 0–192 (frames), resolution ±60 ns. 400 mV to 10.24 Vpp, ±(10% + 50 mV) 100 mV to 2.56 Vpp, ±(10% + 30 mV) (peak-peak sine wave calibrated)
the AES/EBU output to the input. Range is 0–192 (frames), resolution ±60 ns. 400 mV to 10.24 Vpp, ±(10% + 50 mV) 100 mV to 2.56 Vpp, ±(10% + 30 mV)

sample rate) Residual Jitter, peak calibrated Wiscontinuous Jitter Products Spurious Jitter Products Channel Status Bits Channel Status Bits English language decoded (Professional/Consumer) Validity Flag Parity; Signal Confidence; Receiver Lock; Coding Error AUXILIARY SIGNALS Generator Analog Sync Output; Digital Sync Output; Analyzer Input Monitor; Analyzer Reading

Power Output	Typically 1 watt	
GENERAL / ENVIRONMENTAL		
Power Requirements	100/120/230/240 Vac (-10%/+6%), 50-60 Hz, 50 VA max	
Temperature Range	0° C to +40° C Operating; -20° C to +60° C Storage	
Humidity	90% RH to at least +40° C (non- condensing)	
EMC	Complies with 89/336/EEC, CISPR 22 (class B), and FCC 15 subpart J (class B)	
Dimensions	16.5 x 6.0 x 13.6 inches [41.9 x 15.2 x 34.5 cm]	
Weight	Approximately 20 lbs [9.1 kg]	
Safety	Complies with 73/23/EEC, 93/68/EEC, EN61010, and IEC 1010 (including Amendments 1 and 2)	

Complete Portable One specifications are downloadable from the Products area of the Audio Precision Web site at audioprecision.com.



Ordering Informa	Portable One <i>Plus</i> Access Audio Test System with GPIB interface	
	· · · · · · · · · · · · · · · · · · ·	
P1DD	Portable One Dual Domain (digital and analog) Audio Test System with GPIB interface	
Options and Acc	essories for Portable One Instruments	
P1-IMD	SMPTE/DIN intermodulation distortion measurement and generation (analog and digital)	
P-CAS	Protective soft carrying case with shoulder strap and internal/external pockets	
RAK-P1	Rack mount shelf for Portable One <i>Plus</i> Access or Portable One Dual Domain	
MAN-P1PA	Additional Portable One <i>Plus</i> Access operator's manual (one included with instrument)	
MAN-P1DD	Additional Portable One Dual Domain operator's manual (one included with instrument)	
MAN-ATS488	Additional GPIB manual for Portable One <i>Plus</i> Access or Portable One Dual Domain (one included with instrument)	
SVC-P1	Service manual for Portable One <i>Plus</i> Access or Portable One Dual Domain	
CAB-XMF	Set of four XLR male to XLR female cables	
CAB-XBR	Set of four XLR male/female to RCA/BNC cables	
CAB-AES	Set of two AES3 digital cables, 1 meter	
CAB-AES2	Set of two AES3 digital cables, 2 meters	
CAB-AES4	Set of two AES3 digital cables, 4 meters	

Soft carrying case option The padded interior protects your Portable One.

An extra pocket stores documentation and cables,

BUYING A PORTABLE ANALYZER FOR ANALOG AND DIGITAL AUDIO:

What to look for when evaluating competitive instruments

Digital Architecture and Features: Not all analyzers that accept a digital input signal are actually digital analyzers. Does the instrument have a real (DSP-implemented) digital domain analyzer, or just a D/A converter from the digital input connector to an analog hardware analyzer? This latter approach in a competitive unit yields distortion performance in the 12-14 bit range (-70 to -85 dB THD+N, for example). There's just not that much 12-bit digital audio around to measure anymore. Portable One Dual Domain's digital analyzer guarantees -130 dB residual distortion (nearly 22 bit performance), far in excess of the -108 to -112 dB actual linearity of today's best A/D converters.

Analog Performance: Does the instrument have an analog hardware generator and an analog hardware analyzer? Some competitive units (at twice the price of Portable One Dual Domain) use DSP techniques for all generation and analysis, so analog

signals pass through converters inside the instrument. The result is THD+N as high as -79 dB, flatness as poor as -0.2 dB—inadequate for most modern audio devices.

Interface Testing: Does the instrument have independent analog, digital, and jitter generators? If it can only provide analog or digital output at any one time, you can't test a house-synchronized A/D converter for jitter rejection. Without independent, flexible digital audio and jitter generators, you can't measure jitter sensitivity of a D/A converter at various audio and jitter frequency combinations.

True Dual Domain: True Dual Domain hardware by definition guarantees a full range of analysis capabilities in both analog and digital domains. Everyone measures level and some measure THD+N (although implemented with extremely limited performance, as noted above). Be sure that other useful measurements such as IMD (Intermodulation Distortion), Phase, and Crosstalk are available for both analog and digital signals, not just analog.



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